## Notice of References Cited Application/Control No. 10/528,916 Examiner ALVIN L. CARLOS Applicant(s)/Patent Under Reexamination TAN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,532,923 A	07-1996	Sone, Takurou	700/9
*	В	US-5,588,842 A	12-1996	Nishimura et al.	434/307A
*	С	US-5,613,909 A	03-1997	Stelovsky, Jan	463/1
*	D	US-5,689,081 A	11-1997	Tsurumi, Kanehisa	84/609
*	Е	US-5,824,934 A	10-1998	Tsurumi et al.	84/609
*	F	US-5,886,275 A	03-1999	Kato et al.	84/609
*	G	US-5,890,910 A	04-1999	Tsurumi et al.	434/307A
*	Ι	US-5,900,564 A	05-1999	Kurakake, Yasushi	84/477R
*	ı	US-5,947,746 A	09-1999	Tsai, Tom Jen	434/307A
*	J	US-5,953,005 A	09-1999	Liu, James C.	715/243
*	K	US-6,206,704 B1	03-2001	Tsai, Tom Jen	434/307A
*	L	US-6,231,347 B1	05-2001	Tsai, Tom Jen	434/307A
*	М	US-6,572,381 B1	06-2003	Tsai, Tom Jen	434/307A

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
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	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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